Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 23-Aug-99
		Coprocessor (32-bit)											
	Note: Entries in **RED** indicate data added since the 1997 Compendium.												
CNES	68881	FPU	HCMOS/bulk	MOT						12			
CNES	68882	FPU	CHMOS/epi	MOT	3	1.0E-02			Jul-91	<12			
CNES	68882	FPU	CMOS/bulk	MOT	3	1.0E-02			Jul-91	24 to 37			
CNES	68882	FPU	HCMOS/bulk	MOT						16.5			
GE	80387	Math Unit	CHMOS IV	INT	4				Oct-92	6			
JPL	80387	Math Unit	CHMOS IV	INT					Sep-91	24 to 37			
MMS	7C602	FPU	CMOS bulk (0.8 µm)	CYP					1993	10	2.0E-03		
MMS	7C604	MMU (SPARC)	CMOS bulk (0.8 µm)	CYP					1993	40			
GE	80387-16	Math Unit	CHMOS IV	INT					Oct-92	39 to 60			
GSFC	80387-20/B	Math Unit	CHMOS IV	INT	3.4	1.5E-04			May-95	27			
GSFC	80387-20/B	Coproc. (32-bit Math)	CHMOS IV (1.0 µm)	INT	3.4	1.5E–4				39 to 60	2.0E-05	BNL	Moran, et al, RADECS 95, pg 263.
GSFC	80387-20/B	Coproc. (32-bit Math)	CHMOS IV	INT	~10					~32		BNL	LaBel, et al, 96IEEE Wrkshp Rec., pg 19. MicroLU only?
CNES	90C602 SPARC602		CMOS/bulk	MHS	~4	2.0E-03			1993	8			
MMS	L64730	DCT processor	CMOS	LSI	8	2.0E-03			1992	8.7			
JPL	L64804	FPU (SPARC)	"rad-hard" CMOS	LSI	~4	1.5E-04			Mar-94	12			
CNES	L64814	FPU	CMOS	LSI	12	1.0E-01			1993	10			
MMS	L64814	FPU	CMOS/epi	LSI					1992	12			
CNES	MC68882	FPU	CMOS/epi E275(15 µm.)	MOT					Dec-90	>27			
GSFC	**MQ80387-20/B**	**Math Unit**	**CHMOS IV**	**INT**	**9 to 11.4**				**1995**	**32 to 35**		**BNL**	**LaBel, et al, 96IEEE Wrkshp Rec., pg 19. MicroLU.**
ESA	R3010A	FPU Accelerator	CEMOS V	IDT	<8	N/A			1992	27			
ESA	R3010A	FPU Accelerator	HCMOS	LSI	~8	N/A			1992	>27	6.0E-04		
ESA	R3010A	FPU Accelerator		PFS	<6	N/A			1992				
ESA	R3010A	FPU Accelerator	Adv. CMOS	SIE	~6	N/A			1992				

Heavy Ion SEE

Test Org.*	Device	Function	Technology	Mfr.	Effective SEU LET* Threshold	Device Xsection (cm^2)	Bits Tested	Bit Xsection (cm^2)	Test Date	LUth	LU Xsection (cm^2)	Fac.	Remarks 23-Aug-99
Legend													
	Manufacturers: CYP - Cypress; IDT - Integrated Devices Technology; INT - Intel; LSI - LSI Logic; MHS - Matra Harris Semiconductor; MOT - Motorola Semiconductor; PFS - Performance Semiconductor; SIE - Siemens												
	Test Organizations			**Radiation Test Facilities**									
	CNES - Centre National d'etudes Spatiales, Toulouse, France			BNL - Tandem Van de Graaff, Brookhaven National Laboratories, Long Island, NY									
	ESA - European Space Agency, Noordwijk, Netherlands												
	GE - General Electic, Valley Forge, PA												
	GSFC - Goddard Space Flight Center, Greenbelt, MD												
	JPL - Jet Propulsion Laboratory, Pasadena, CA												
	MMS - Matra Marconi Space, France												